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March 2015

FDD8880

N-Channel PowerTrench[®] MOSFET 30V, 58A, $9m\Omega$

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\text{DS}(\text{ON})}$ and fast switching speed.

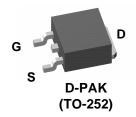
Applications

DC/DC converters



Features

- $r_{DS(ON)} = 9m\Omega$, $V_{GS} = 10V$, $I_D = 35A$
- $r_{DS(ON)} = 12m\Omega$, $V_{GS} = 4.5V$, $I_D = 35A$
- High performance trench technology for extremely low r_{DS(ON)}
- · Low gate charge
- High power and current handling capability
- RoHS Compliant





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V _{DSS}	Drain to Source Voltage	30	V	
V _{GS}	Gate to Source Voltage	±20	V	
	Drain Current			
I _D	Continuous ($T_C = 25^{\circ}$ C, $V_{GS} = 10V$) (Note 1)	58	Α	
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)	51	А	
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 52^{\circ}C/W$)	13	Α	
	Pulsed	Figure 4	Α	
E _{AS}	Single Pulse Avalanche Energy (Note 2)	53	mJ	
P _D	Power dissipation	55	W	
	Derate above 25°C	0.37	W/°C	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-252	2.73	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252	100	°C/W
R _{e,IA}	Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

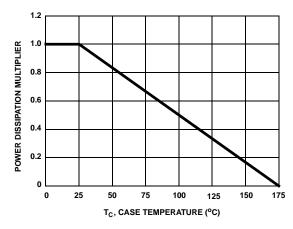
Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8880	FDD8880	TO-252AA	13"	16mm	2500 units

Symbol	Parameter	Test Conditions		Тур	Max	Units
Off Chara	cteristics					
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		-	-	V
1	7 0 1 1/1 5 1 0 1	V _{DS} = 24V	-	-	1	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V$ $T_C = 150^{\circ}C$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20V	-	-	±100	nA
On Chara	cteristics					
V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	-	2.5	V
	1	I _D = 35A, V _{GS} = 10V	-	0.007	0.009	Ω
_	Drain to Source On Registence	$I_D = 35A, V_{GS} = 4.5V$	-	0.009	0.012	
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	-	0.013	0.015	
Dynamic	Characteristics					
C _{ISS}	Input Capacitance		-	1260	-	pF
C _{OSS}	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$	-	260	-	pF
C _{RSS}	Reverse Transfer Capacitance	f = 1MHz	-	150	-	pF
R _G	Gate Resistance	V _{GS} = 0.5V, f = 1MHz	-	2.3	-	Ω
Q _{g(TOT)}	Total Gate Charge at 10V	V _{GS} = 0V to 10V	-	23	31	nC
Q _{g(5)}	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$	-	13	17	nC
Q _{q(TH)}	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 1V$ $V_{DD} = 15V$	-	1.3	1.7	nC
Q _{qs}	Gate to Source Gate Charge	$I_D = 35A$ $I_q = 1.0 \text{mA}$	-	3.8	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		-	2.5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		-	5.0	-	nC
Switching	Characteristics (V _{GS} = 10V)					
t _{ON}	Turn-On Time		-	-	147	ns
t _{d(ON)}	Turn-On Delay Time	7	-	8	-	ns
t _r	Rise Time	$V_{DD} = 15V, I_{D} = 35A$	-	91	-	ns
t _{d(OFF)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 10\Omega$	-	38	-	ns
t _f	Fall Time	7	-	32	-	ns
t _{OFF}	Turn-Off Time	7	-	-	108	ns
Drain-Sou	urce Diode Characteristics					
		I _{SD} = 35A	-	-	1.25	V
V_{SD}	Source to Drain Diode Voltage	I _{SD} = 15A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$	-	-	27	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$	-	T -	14	nC

- Notes: 1: Package current limitation is 35A. 2: Starting $T_J = 25^{\circ}C$, L = 0.14mH, $I_{AS} = 28$ A, $V_{DD} = 27$ V, $V_{GS} = 10$ V.

Typical Characteristics T_C = 25°C unless otherwise noted



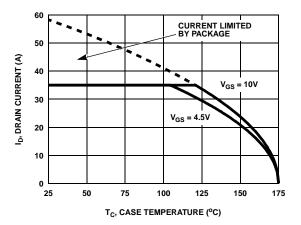


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

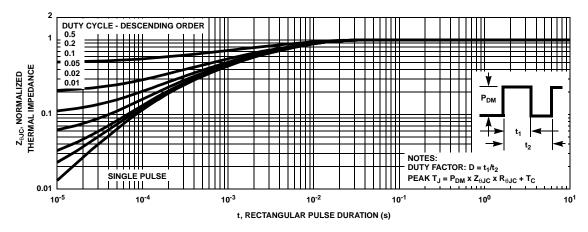


Figure 3. Normalized Maximum Transient Thermal Impedance

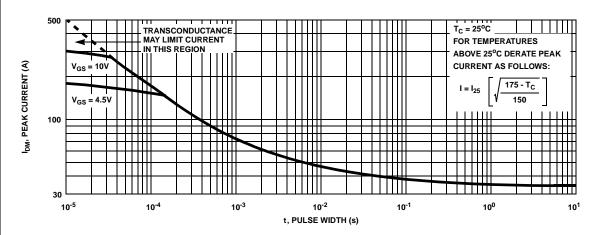
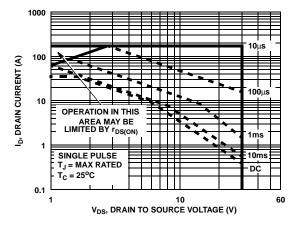


Figure 4. Peak Current Capability

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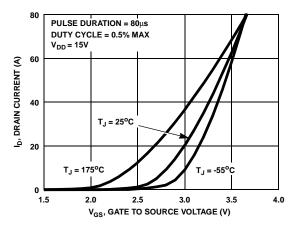
The control of the co

Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



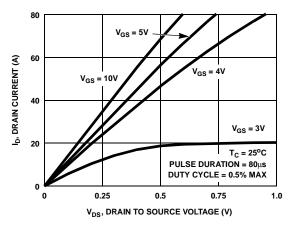
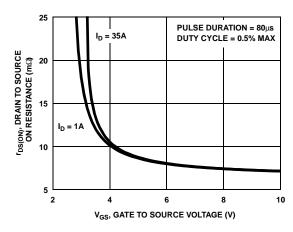


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



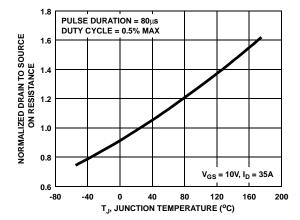


Figure 9. Drain to Source On Resistance vs Gate Voltage and Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

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Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

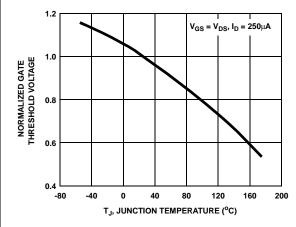


Figure 11. Normalized Gate Threshold Voltage vs
Junction Temperature

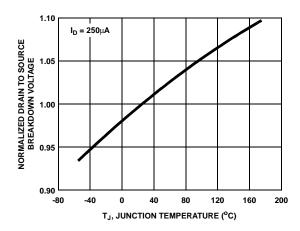


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

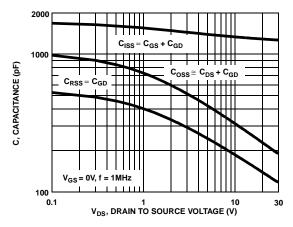


Figure 13. Capacitance vs Drain to Source Voltage

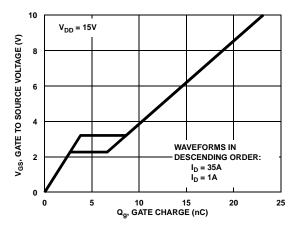


Figure 14. Gate Charge Waveforms for Constant Gate Current

Test Circuits and Waveforms

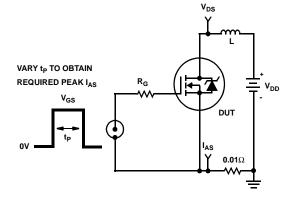


Figure 15. Unclamped Energy Test Circuit

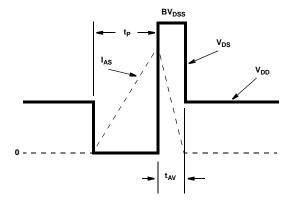


Figure 16. Unclamped Energy Waveforms

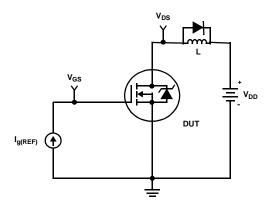


Figure 17. Gate Charge Test Circuit

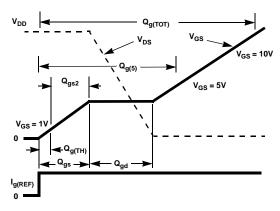


Figure 18. Gate Charge Waveforms

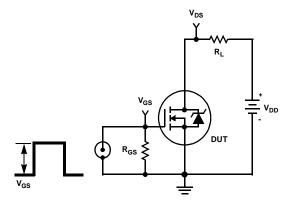


Figure 19. Switching Time Test Circuit

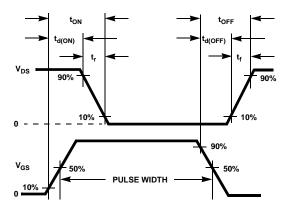


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\Theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

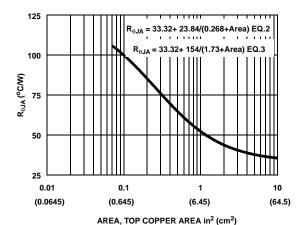
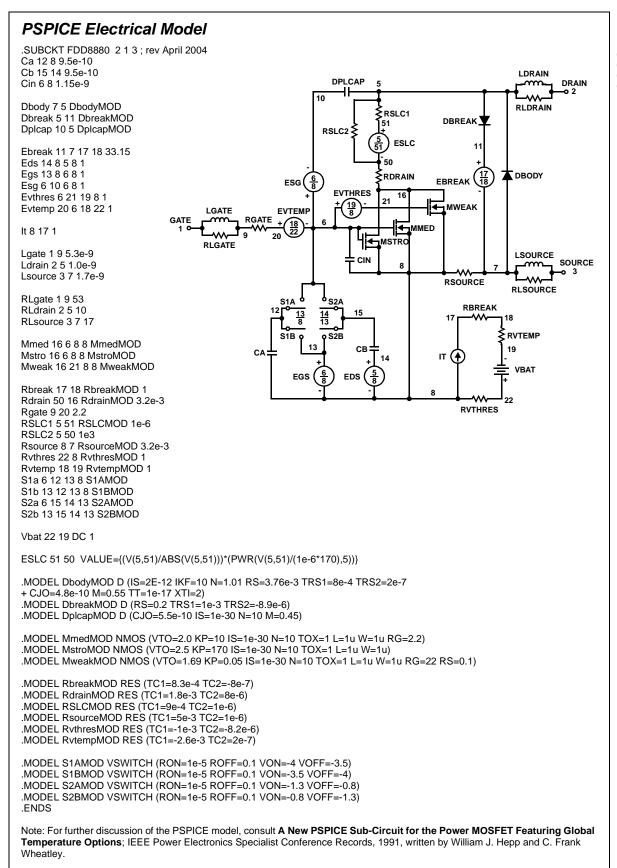
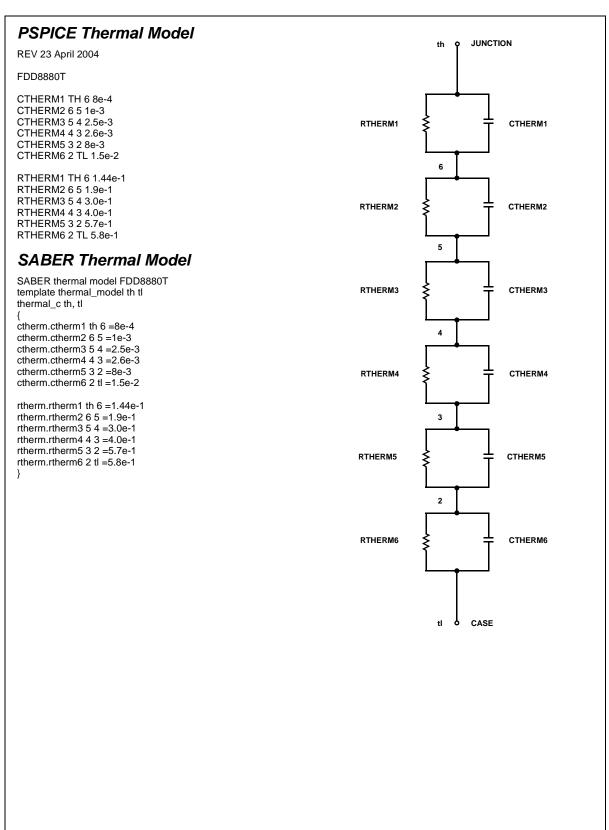


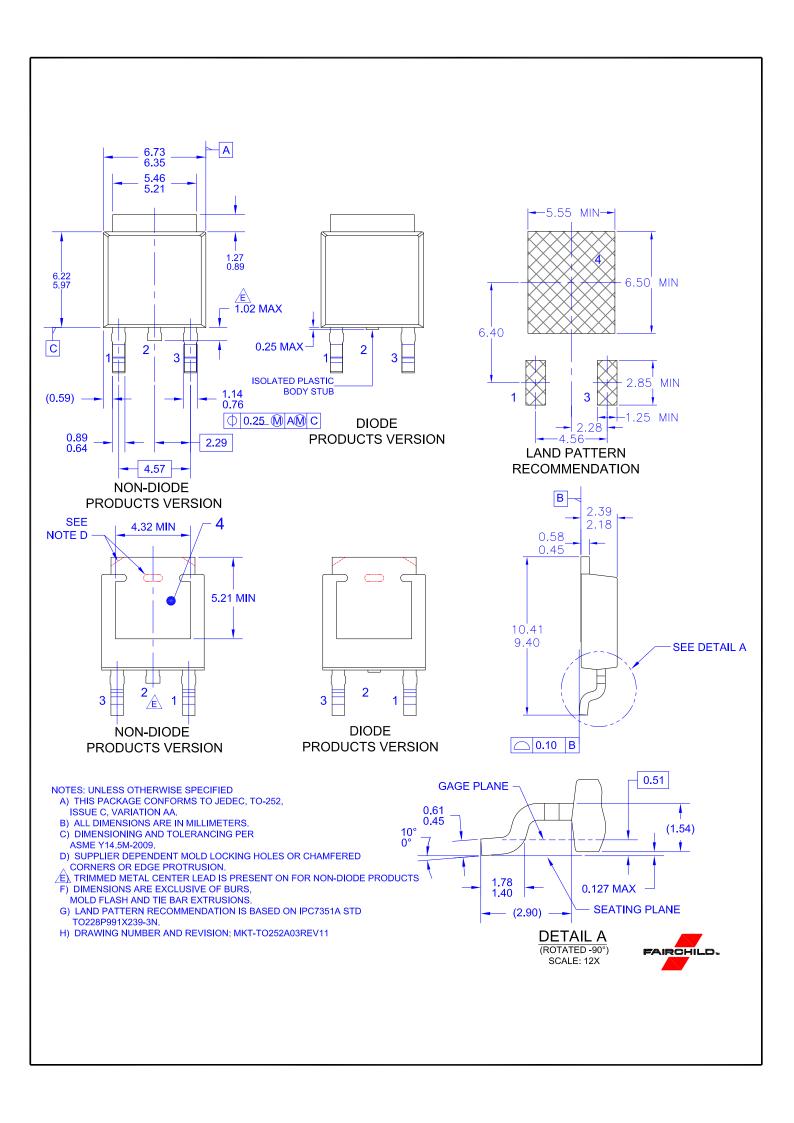
Figure 21. Thermal Resistance vs Mounting
Pad Area



SABER Electrical Model rev April 2004 template FDD8880 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2e-12,ikf=10,nl=1.01,rs=3.76e-3,trs1=8e-4,trs2=2e-7,cjo=4.8e-10,m=0.55,tt=1e-17,xti=2) dp..model dbreakmod = (rs=0.2,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=5.5e-10,isl=10e-30,nl=10,m=0.45) m..model mmedmod = $(type=_n, vto=2.0, kp=10, is=1e-30, tox=1)$ m..model mstrongmod = (type= n, vto=2.5, kp=170, is=1e-30, tox=1)m..model mweakmod = (type=_n,vto=1.69,kp=0.05,is=1e-30, tox=1,rs=0.1) LDRAIN sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-3.5) **DPLCAP** DRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3.5,voff=-4) 10 sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-1.3,voff=-0.8) RLDRAIN sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.8,voff=-1.3) RSLC1 c.ca n12 n8 = 9.5e-10 51 RSLC2 € c.cb n15 n14 = 9.5e-10ISCI c.cin n6 n8 = 1.15e-9 DBREAK 50 dp.dbody n7 n5 = model=dbodymod RDRAIN <u>6</u>8 dp.dbreak n5 n11 = model=dbreakmod **FSG** DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** (<u>19</u>) **MWEAK** LGATE **EVTEMP** spe.ebreak n11 n7 n17 n18 = 33.15 _{GATE} 18 22 **ММ**ЕД EBREAK spe.eds n14 n8 n5 n8 = 1 spe.egs n13 n8 n6 n8 = 1 **←**MSTRC RLGATE spe.esg n6 n10 n6 n8 = 1 LSOURCE spe.evthres n6 n21 n19 n8 = 1 CIN SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1 RBREAK I.lgate n1 n9 = 5.3e-9I.Idrain n2 n5 = 1.0e-9**₹**RVTEMP S1B oS2B I.Isource n3 n7 = 1.7e-919 СА IT (♠ 14 res.rlgate n1 n9 = 53 VBAT res.rldrain n2 n5 = 10 **EGS EDS** res.rlsource n3 n7 = 17 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u **RVTHRES** m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod. l=1u, w=1u res.rbreak n17 n18 = 1, tc1=8.3e-4,tc2=-8e-7 res.rdrain n50 n16 = 3.2e-3, tc1=1.8e-3,tc2=8e-6 res.rgate n9 n20 = 2.2res.rslc1 n5 n51 = 1e-6, tc1=9e-4,tc2=1e-6 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 3.2e-3, tc1=5e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-1e-3,tc2=-8.2e-6 res.rvtemp n18 n19 = 1. tc1=-2.6e-3.tc2=2e-7 sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { (v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/170))**5))

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